

The manufacturer
may use the mark:



Reports:

HON 08-12-17 R001 FMEDA
V1 R1 Report

HON 10-02-43 R002
Assessment V2 R3 Report

Validity:

This assessment is valid for
the STT25T Temperature
Transmitter with HART 6 .

This assessment is valid until
February 1, 2014

Revision 1.3 June 18, 2012



Certificate / Certificat Zertifikat / 合格証

HON 100243 C002

exida hereby confirms that the:

STT25T Temperature Transmitter With HART 6

**Honeywell International Inc.
Honeywell Field Products
Fort Washington, PA 19034, USA**

Has been assessed per the relevant requirements of:

IEC 61508 Parts 1, 2, 3

and meets requirements providing a level of integrity to:

Systematic Integrity: SIL 3 Capable

**Random Integrity for Type B Device:
SIL 3 @ HFT=1 / SIL 2 @ HFT=0**

Safety Function:

A STT25T Temperature Transmitter with HART 6 will measure
temperature within the stated safety accuracy.

Application Restrictions:

The unit must be properly designed into a Safety Instrumented
Function per the Safety Manual requirements.



Michael Medoff
Evaluating Assessor

Griff Francis

Certifying Assessor

HON 100243 C002

Systematic Integrity: SIL 3 Capable

Random Integrity for Type B Device:

SIL 3 @ HFT=1 / SIL 2 @ HFT=0

STT25T Temperature Transmitter With HART 6

**Honeywell International Inc.,
Honeywell Field Products,
Fort Washington, PA
19034, USA**

SIL 3 Capability:

The product has met manufacturer design process requirements of Safety Integrity Level (SIL) 3. These are intended to achieve sufficient integrity against systematic errors of design by the manufacturer.

A Safety Instrumented Function (SIF) designed with this product must not be used at a SIL level higher than stated without "prior use" justification by end user or diverse technology redundancy in the design.

IEC 61508 Failure Rates in FIT*

Device	λ_{SD}	λ_{SU}	λ_{DD}	λ_{DU}	SFF
STT25T Temperature Transmitter with HART 6, RTD Input and RMA300-ME	0 FIT	224.6 FIT	287.9 FIT	33.5 FIT	93.9%
STT25T Temperature Transmitter with HART 6, TC Input and RMA300-ME	0 FIT	211.1 FIT	279.7 FIT	30.8 FIT	94.1%
STT25T Temperature Transmitter with HART 6, RTD Input and RMA300-SM	0 FIT	224.6 FIT	286.6 FIT	42.7 FIT	92.3%
STT25T Temperature Transmitter with HART 6, TC Input and RMA300-SM	0 FIT	211.1 FIT	278.4 FIT	40.0 FIT	92.5%
STT25T Temperature Transmitter with HART 6, RTD Input and SPD	0 FIT	224.6 FIT	300.4 FIT	34.5 FIT	93.8%
STT25T Temperature Transmitter with HART 6, TC Input and SPD	0 FIT	211.1 FIT	292.2 FIT	31.8 FIT	93.8%

SIL Verification:

The Safety Integrity Level (SIL) of an entire Safety Instrumented Function (SIF) must be verified via a calculation of PFD_{AVG} considering redundant architectures, proof test interval, proof test effectiveness, any automatic diagnostics, average repair time and the specific failure rates of all products included in the SIF. Each subsystem must be checked to assure compliance with minimum hardware fault tolerance (HFT) requirements.

* FIT = 1 failure / 10^9 hours



Form	Version	Date
C61508	2.5-3	Aug 2010